UND02R100L

Preliminary

POWER MOSFET

DFN-8(3x3)

25A, 20V N-CHANNEL **ENHANCEMENT MODE** TRENCH POWER MOSFET

DESCRIPTION

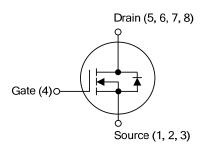
The UTC UND02R100L is an N-channel Power MOSFET, it uses UTC's advanced technology to provide the customers with low Rdson characteristic by high cell density trench technology.

The UTC UND02R100L is suitable for high efficiency synchronous rectification in SMPS, UPS, hard switched and high frequency circuits.

FEATURES

- * $R_{DS(ON)} \le 8.2 \text{ m}\Omega$ @ $V_{GS}=4.5V$, $I_{D}=8.0A$ $R_{DS(ON)} \le 9.5 \text{ m}\Omega$ @ $V_{GS} = 2.5 \text{V}$, $I_D = 7.0 \text{A}$ $R_{DS(ON)} \le 12 \text{ m}\Omega$ @ $V_{GS}=1.8V$, $I_{D}=4.0A$
- * High Cell Density Trench Technology
- * High Power and Current Handling Capability

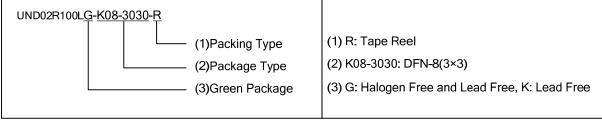
SYMBOL



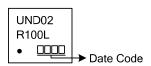
ORDERING INFORMATION

Ordering Number		Dookogo	Pin Assignment							Dooking	
Lead Free	Halogen Free	Package	1	2	3	4	5	6	7	8	Packing
UND02R100LK-K08-3030-R	UND02R100LG-K08-3030-R	DFN-8(3×3)	S1	G1	S2	G2	D2	D2	D1	D1	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source



MARKING



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■ **ABSOLUTE MAXIMUM RATING** (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	20	V
Gate-Source Voltage		V_{GSS}	±8	V
Drain Current	Continuous	I _D	25	Α
Jiain Current	Pulsed (Note 2)	I _{DM}	60	Α
Power Dissipation		P_{D}	31	W
Junction Temperature		TJ	+150	°C
Storage Temperature Range		T _{STG}	-55 ~ + 150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating: Pulse width limited by maximum junction temperature.

■ THERMAL RESISTANCES CHARACTERISTICS

PARAMETER	SYMBOL	RATINGS	UNIT		
Junction to Ambient	θ_{JA}	40	°C/W		
Junction to Case	θ_{JC}	4	°C/W		

Note: Surface mounted on 1×1 FR4 board.

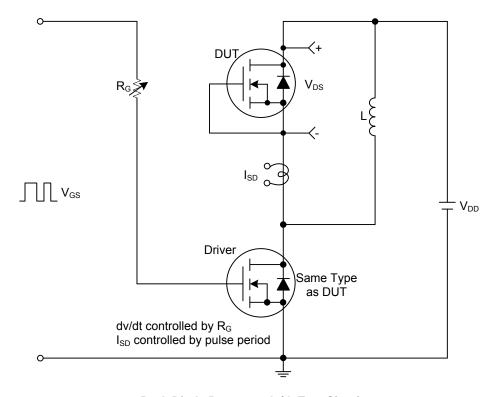
■ ELECTRICAL CHARACTERISTICS (T_J =25°C, unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT			
OFF CHARACTERISTICS										
Drain-Source Breakdown Voltage		BV _{DSS}	I _D =250μA, V _{GS} =0V	20			V			
Drain-Source Leakage Current		I_{DSS}	V _{DS} =20V, V _{GS} =0V			1	μΑ			
Gate-Source Leakage Current	Forward	lass	V_{GS} =+8 V , V_{DS} =0 V			+100	nA			
	Reverse	I _{GSS}	V _{GS} =-8V, V _{DS} =0V			-100	nA			
ON CHARACTERISTICS										
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$	0.4		0.9	V			
Static Drain-Source On-State Resistance			V _{GS} =4.5V, I _D =8.0A		6.6	8.2	mΩ			
		$R_{DS(ON)}$	V _{GS} =2.5V, I _D =7.0A		7.7	9.5	mΩ			
			V _{GS} =1.8V, I _D =4.0A		9.6	12	mΩ			
DYNAMIC PARAMETERS										
Input Capacitance		C _{ISS}			2705		pF			
Output Capacitance		Coss	V _{GS} =0V, V _{DS} =10V, f=1.0MHz		241		pF			
Reverse Transfer Capacitance		C _{RSS}			205		pF			
SWITCHING PARAMETERS										
Total Gate Charge (Note 1)		Q_{G}	V _{DS} =10V, V _{GS} =4.5V, I _D =10A,		66.8		nC			
Gate to Source Charge		Q_{GS}	I _G =100μA (Note 1, 2)		3.2		nC			
Gate to Drain Charge		Q_{GD}	IG-100μA (Note 1, 2)		4.8		nC			
Turn-on Delay Time (Note 1)		t _{D(ON)}			58		ns			
Rise Time		t_R	V_{DD} =10V, V_{GS} =4.5V, I_{D} =10A,		61		ns			
Turn-off Delay Time		t _{D(OFF)}	$R_G = 1\Omega$ (Note 1, 2)		450		ns			
Fall-Time		t_{F}			330		ns			
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS										
Maximum Body-Diode Continuous Current		Is				25	Α			
Maximum Body-Diode Pulsed Cur	rent	I _{SM}				60	Α			
Drain-Source Diode Forward Volta	ige (Note 1)	V_{SD}	I _S =10A, V _{GS} =0V		8.0	1.2	V			
Reverse Recovery Time (Note 1)		t _{rr}	I _S =10A, V _{GS} =0V,		2.08		μS			
Reverse Recovery Charge		Q_{rr}	dI _F /dt =100A/μs		18.3		μC			

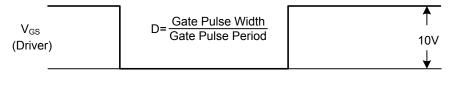
Notes: 1. Pulse Test : Pulse width ≤ 200µs, Duty cycle ≤ 2%.

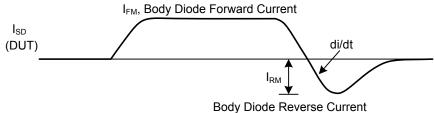
^{2.} Essentially independent of operating ambient temperature.

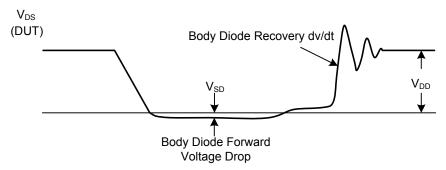
■ TEST CIRCUITS AND WAVEFORMS



Peak Diode Recovery dv/dt Test Circuit



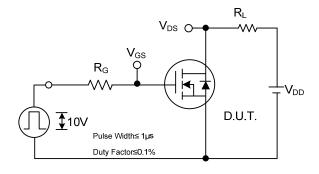


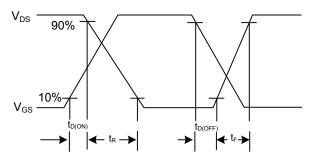


Peak Diode Recovery dv/dt Test Circuit and Waveforms

Peak Diode Recovery dv/dt Waveforms

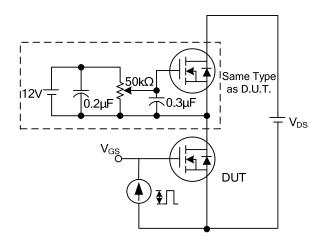
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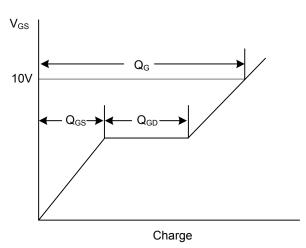




Switching Test Circuit

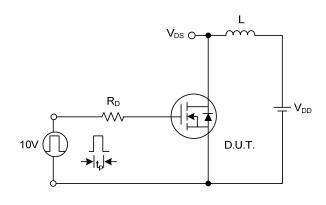
Switching Waveforms

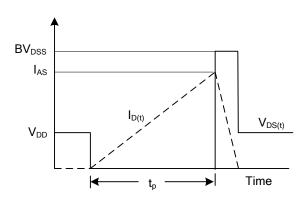




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

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